

## Notice of References Cited

Application/Control No. 09/937,450	Reexaminatio	Applicant(s)/Patent Under Reexamination RUTTER ET AL.		
Examiner	Art Unit			
Phung T Nauven	2632	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,729,207	12-1996	Yamano	340/628
	В	US-5,440,293	05-1992	Tice	340/568
	С	US-6,078,269	11-1997	Markwell et al.	340/825.5
	D	US-4,369,435	07-1980	Adachi et al.	340/506
	Е	US-4,829,283	01-1988	Spang et al.	340/506
	F	US-5,172,096	08-1991	Tice et al.	340/501
	G	US-5,912,626	10-1997	Soderlund	340/693.5
	Н	US-4,887,073	11-1988	Nakao et al.	340/693
	ļ	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

	HON-FATERT DOCUMENTS			
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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	w			
	х			

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